



## High Temp Wafer Level Testing

*At Microcross, we specialise in the selection and identification of bare die that will perform best under high temperature.*

High Temp devices provide a solution to our customers who require product that need to meet extreme temperature operation. Microcross offer singulated die, 100% tested to extreme temperature range (200°C).

### Probe testing Capabilities

- Testing of both bare die & hybrid substrates
- Precision hot probing up to 200°C (higher temp on special request)
- Temperature accuracy  $\pm 0.5^{\circ}\text{C}$
- Temperature stability  $\pm 0.1^{\circ}\text{C}$
- Fully automated multiple wafer handling
- Lot characterisation
- Customisable output data and logging
- Complete wafer mapping, selection and traceability to single die for KGD.

### Typical Applications

- Oil and gas exploration & production
- Under sea cabling
- Heavy industrial sensors
- Medical
- Jet engine sensors

Graded wafer (wafer map)

